



SGM4717EP

4.5Ω, 300MHz Bandwidth, Dual, SPDT Analog Switch

GENERAL DESCRIPTION

The SGM4717EP is a dual, bidirectional, single-pole/double-throw (SPDT) CMOS analog switch designed to operate from a single +1.8V to +5.5V supply. It features high-bandwidth (300MHz) and low on-resistance (4.5Ω TYP), Targeted applications for audio switching.

SGM4717EP features guaranteed on-resistance matching (0.3Ω MAX) between switches and guaranteed on-resistance flatness over the signal range (2.3Ω TYP). This ensures excellent linearity and low distortion when switching audio signals.

The SGM4717EP is a committed dual single-pole/double-throw (SPDT) that consist of two normally open (NO) and two normally close (NC) switches. This configuration can be used as a dual 2-to-1 multiplexer.

SGM4717EP is available in WQFN-10 package.

APPLICATIONS

Portable Instrumentation
Battery-Operated Equipment
Computer Peripherals
Cell Phones
PDAs
MP3s

FUNCTION TABLE

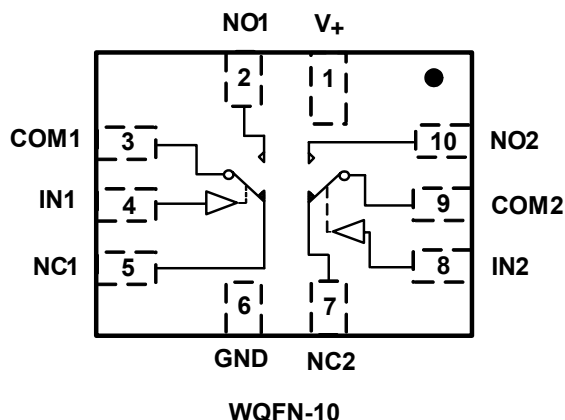
LOGIC	NO	NC
0	OFF	ON
1	ON	OFF

Switches Shown For Logic "0" Input

FEATURES

- Voltage Operation: 1.8V to 5.5V
- On-Resistance: 4.5Ω (TYP) at 5.0V
- High Bandwidth: 300MHz
- Fast Switching Times
 - t_{ON} 26ns
 - t_{OFF} 20ns
- High Off-Isolation: -57dB at 10MHz
- Low Crosstalk: -99dB at 10MHz
- Rail-to-Rail Operation
- TTL/CMOS Compatible
- Break-Before-Make Switching
- Extended Industrial Temperature Range:
 - 40°C to +85°C
- WQFN-10 Package

PIN CONFIGURATION (TOP VIEW)



ORDERING INFORMATION

MODEL	PIN-PACKAGE	SPECIFIED TEMPERATURE RANGE	ORDERING NUMBER	PACKAGE MARKING	PACKAGE OPTION
SGM4717EP	WQFN-10	-40°C to +85°C	SGM4717EP-YWQ10/TR	4717E	Tape and Reel, 3000

ABSOLUTE MAXIMUM RATINGS

V₊, IN to GND.....-0.3V to 6V
 Analog, Digital voltage range ⁽¹⁾..... -0.3V to (V₊) + 0.3V
 Continuous Current NO, NC, or COM.....±50mA
 Peak Current NO, NC, or COM±80mA
 Operating Temperature Range.....-40°C to +85°C

Junction Temperature.....150°C
 Storage Temperature.....-65°C to +150°C
 Lead Temperature (soldering, 10s).....260°C
 ESD (HBM)2000V

Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.
 (1) Signals on NC, NO, or COM or IN exceeding V₊ will be clamped by internal diodes. Limit forward diode current to maximum current ratings.

CAUTION

This integrated circuit can be damaged by ESD if you don't pay attention to ESD protection. SGMICRO recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

PIN DESCRIPTION

NAME	FUNCTION
V ₊	Power supply
GND	Ground
IN1, IN2	Digital control pin to connect the COM terminal to the NO or NC terminals
COM1, COM2	Common terminal
NO1, NO2	Normally-open terminal
NC1, NC2	Normally-closed terminal

Note: NO, NC and COM terminals may be an input or output.

ELECTRICAL CHARACTERISTICS

($V_+ = +4.5V$ to $+5.5V$, $V_{IH} = +2.0V$, $V_{IL} = +0.8V$, $T_A = -40^\circ C$ to $+85^\circ C$. Typical values are at $V_+ = 5.0V$, $T_A = +25^\circ C$, unless otherwise noted.)

PARAMETER	SYMBOL	CONDITIONS	TEMP	MIN	TYP	MAX	UNITS
ANALOG SWITCH							
Analog Signal Range	V_{NO}, V_{NC}, V_{COM}		$-40^\circ C$ to $+85^\circ C$	0		V_+	V
On-Resistance	R_{ON}	$V_+ = 4.5V$, V_{NO} or $V_{NC} = 3.5V$, $I_{COM} = -10mA$, Test Circuit 1	$+25^\circ C$		4.5	8	Ω
			$-40^\circ C$ to $+85^\circ C$			8.5	Ω
On-Resistance Match Between Channels	ΔR_{ON}	$V_+ = 4.5V$, V_{NO} or $V_{NC} = 3.5V$, $I_{COM} = -10mA$, Test Circuit 1	$+25^\circ C$		0.15	0.3	Ω
			$-40^\circ C$ to $+85^\circ C$			0.8	Ω
On-Resistance Flatness	$R_{FLAT(ON)}$	$V_+ = 4.5V$, V_{NO} or $V_{NC} = 1.0V, 2.0V, 3.5V$, $I_{COM} = -10mA$, Test Circuit 1	$+25^\circ C$		2.3	3.3	Ω
			$-40^\circ C$ to $+85^\circ C$			3.7	Ω
Source OFF Leakage Current	$I_{NC(OFF)}, I_{NO(OFF)}$	$V_+ = 5.5V$, V_{NO} or $V_{NC} = 1.0V, 4.5V$, $V_{COM} = 4.5V, 1.0V$	$-40^\circ C$ to $+85^\circ C$			1	μA
Channel ON Leakage Current	$I_{NC(ON)}, I_{NO(ON)}, I_{COM(ON)}$	$V_+ = 5.5V$, $V_{COM} = 1.0V, 4.5V$, V_{NO} or $V_{NC} = 1.0V, 4.5V$, or floating	$-40^\circ C$ to $+85^\circ C$			1	μA
DIGITAL INPUTS							
Input High Voltage	V_{INH}		$-40^\circ C$ to $+85^\circ C$	1.5			V
Input Low Voltage	V_{INL}		$-40^\circ C$ to $+85^\circ C$			0.6	V
Input Leakage Current	I_{IN}	$V_+ = 5.5V$, $V_{IN} = 0V$ or $5.5V$	$-40^\circ C$ to $+85^\circ C$			1	μA
DYNAMIC CHARACTERISTICS							
Turn-On Time	t_{ON}	V_{NO} or $V_{NC} = 3.0V$, $V_{IH} = 1.5V$, $V_{IL} = 0V$, $R_L = 300\Omega$, $C_L = 35pF$, Test Circuit 2	$+25^\circ C$		26		ns
Turn-Off Time	t_{OFF}	V_{NO} or $V_{NC} = 3.0V$, $V_{IH} = 1.5V$, $V_{IL} = 0V$, $R_L = 300\Omega$, $C_L = 35pF$, Test Circuit 2	$+25^\circ C$		20		ns
Break-Before-Make Time Delay	t_D	V_{NO1} or $V_{NC1} = V_{NO2}$ or $V_{NC2} = 3V$, $R_L = 300\Omega$, $C_L = 35pF$, Test Circuit 3	$+25^\circ C$		4		ns
Skew	t_{SKEW}	$R_S = 39\Omega$, $C_L = 50pF$, Test Circuit 4	$+25^\circ C$		5.8		ns
Off Isolation	O_{ISO}	$R_L = 50\Omega$, Signal = 0dBm, $C_L = 5pF$, Test Circuit 5	$f = 10MHz$	$+25^\circ C$		-57	dB
			$f = 1MHz$	$+25^\circ C$		-76	dB
Channel-to-Channel Crosstalk	X_{TALK}	$R_L = 50\Omega$, $C_L = 5pF$, Test Circuit 6	$f = 10MHz$	$+25^\circ C$		-99	dB
			$f = 1MHz$	$+25^\circ C$		-110	dB
-3dB Bandwidth	BW	Signal = 0dBm, $R_L = 50\Omega$, $C_L = 5pF$, Test Circuit 7	$+25^\circ C$		300		MHz
Channel ON Capacitance	C_{ON}	$f = 1MHz$	$+25^\circ C$		10		pF
POWER REQUIREMENTS							
Power Supply Range	V_+		$-40^\circ C$ to $+85^\circ C$	1.8		5.5	V
Power Supply Current	I_+	$V_+ = 5.5V$, $V_{IN} = 0V$ or V_+	$-40^\circ C$ to $+85^\circ C$			5	μA

Specifications subject to changes without notice.

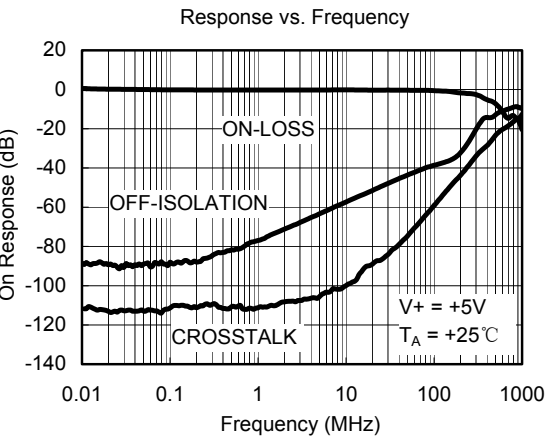
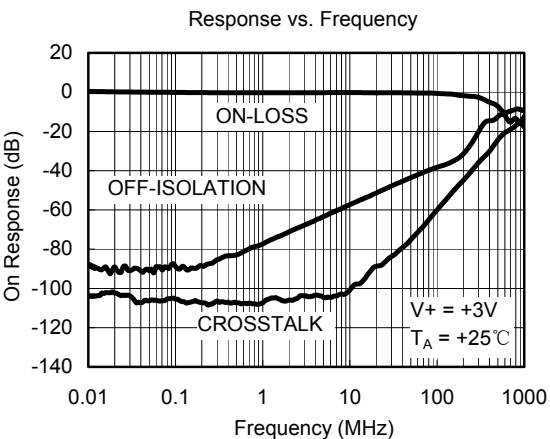
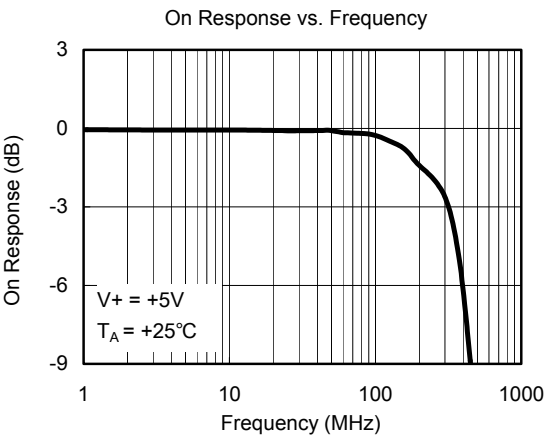
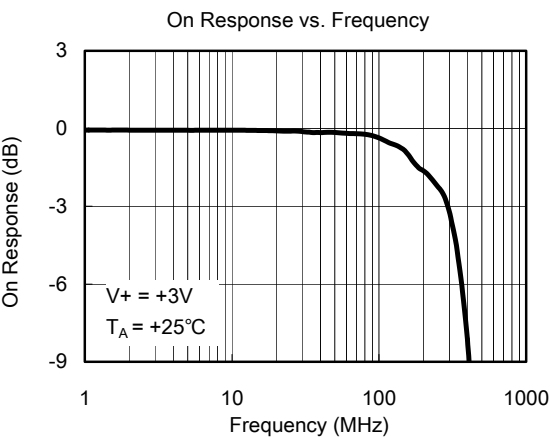
ELECTRICAL CHARACTERISTICS

($V_+ = +2.7V$ to $+3.6V$, $V_{IH} = +1.4V$, $V_{IL} = +0.5V$, $T_A = -40^\circ C$ to $+85^\circ C$. Typical values are at $V_+ = 3.0V$, $T_A = +25^\circ C$, unless otherwise noted.)

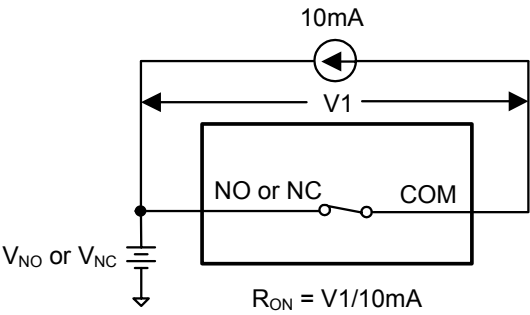
PARAMETER	SYMBOL	CONDITIONS	TEMP	MIN	TYP	MAX	UNITS
ANALOG SWITCH							
Analog Signal Range	V_{NO}, V_{NC}, V_{COM}		$-40^\circ C$ to $+85^\circ C$	0		V_+	V
On-Resistance	R_{ON}	$V_+ = 2.7V$, V_{NO} or $V_{NC} = 1.5V$, $I_{COM} = -10mA$, Test Circuit 1	$+25^\circ C$		7	10	Ω
			$-40^\circ C$ to $+85^\circ C$			10.5	Ω
On-Resistance Match Between Channels	ΔR_{ON}	$V_+ = 2.7V$, V_{NO} or $V_{NC} = 1.5V$, $I_{COM} = -10mA$, Test Circuit 1	$+25^\circ C$		0.25	0.6	Ω
			$-40^\circ C$ to $+85^\circ C$			0.8	Ω
On-Resistance Flatness	$R_{FLAT(ON)}$	$V_+ = 2.7V$, V_{NO} or $V_{NC} = 1.0V, 1.5V, 2.0V$, $I_{COM} = -10mA$, Test Circuit 1	$+25^\circ C$		3	4	Ω
			$-40^\circ C$ to $+85^\circ C$			4.3	Ω
Source OFF Leakage Current	$I_{NC(OFF)}, I_{NO(OFF)}$	$V_+ = 3.6V$, V_{NO} or $V_{NC} = 0.3V, 3.3V$, $V_{COM} = 3.3V, 0.3V$	$-40^\circ C$ to $+85^\circ C$			1	μA
Channel ON Leakage Current	$I_{NC(ON)}, I_{NO(ON)}, I_{COM(ON)}$	$V_+ = 3.6V$, $V_{COM} = 0.3V, 3.3V$, V_{NO} or $V_{NC} = 0.3V, 3.3V$, or floating	$-40^\circ C$ to $+85^\circ C$			1	μA
DIGITAL INPUTS							
Input High Voltage	V_{INH}		$-40^\circ C$ to $+85^\circ C$	1			V
Input Low Voltage	V_{INL}		$-40^\circ C$ to $+85^\circ C$			0.5	V
Input Leakage Current	I_{IN}	$V_+ = 5.5V$, $V_{IN} = 0V$ or $3.6V$	$-40^\circ C$ to $+85^\circ C$			1	μA
DYNAMIC CHARACTERISTICS							
Turn-On Time	t_{ON}	V_{NO} or $V_{NC} = 1.5V$, $V_{IH} = 1.5V$, $V_{IL} = 0V$, $R_L = 300\Omega$, $C_L = 35pF$, Test Circuit 2	$+25^\circ C$		23		ns
Turn-Off Time	t_{OFF}	V_{NO} or $V_{NC} = 1.5V$, $V_{IH} = 1.5V$, $V_{IL} = 0V$, $R_L = 300\Omega$, $C_L = 35pF$, Test Circuit 2	$+25^\circ C$		22		ns
Break-Before-Make Time Delay	t_D	V_{NO1} or $V_{NC1} = V_{NO2}$ or $V_{NC2} = 3V$, $R_L = 300\Omega$, $C_L = 35pF$, Test Circuit 3	$+25^\circ C$		4		ns
Skew	t_{SKEW}	$R_S = 39\Omega$, $C_L = 50pF$, Test Circuit 4	$+25^\circ C$		5		ns
Off Isolation	O_{ISO}	$R_L = 50\Omega$, Signal = 0dBm, $C_L = 5pF$, Test Circuit 5	$f = 10MHz$	$+25^\circ C$		-57	dB
			$f = 1MHz$	$+25^\circ C$		-76	dB
Channel-to-Channel Crosstalk	X_{TALK}	$R_L = 50\Omega$, $C_L = 5pF$, Test Circuit 6	$f = 10MHz$	$+25^\circ C$		-98	dB
			$f = 1MHz$	$+25^\circ C$		-103	dB
-3dB Bandwidth	BW	Signal = 0dBm, $R_L = 50\Omega$, $C_L = 5pF$, Test Circuit 7	$+25^\circ C$		300		MHz
POWER REQUIREMENTS							
Power Supply Range	V_+		$-40^\circ C$ to $+85^\circ C$	1.8		5.5	V
Power Supply Current	I_+	$V_+ = 5.5V$, $V_{IN} = 0V$ or V_+	$-40^\circ C$ to $+85^\circ C$			5	μA

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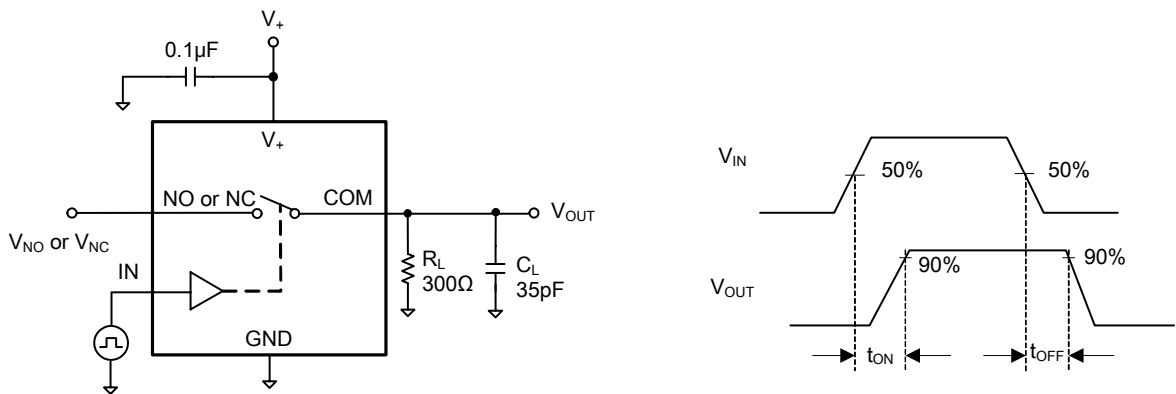
TYPICAL PERFORMANCE CHARACTERISTICS



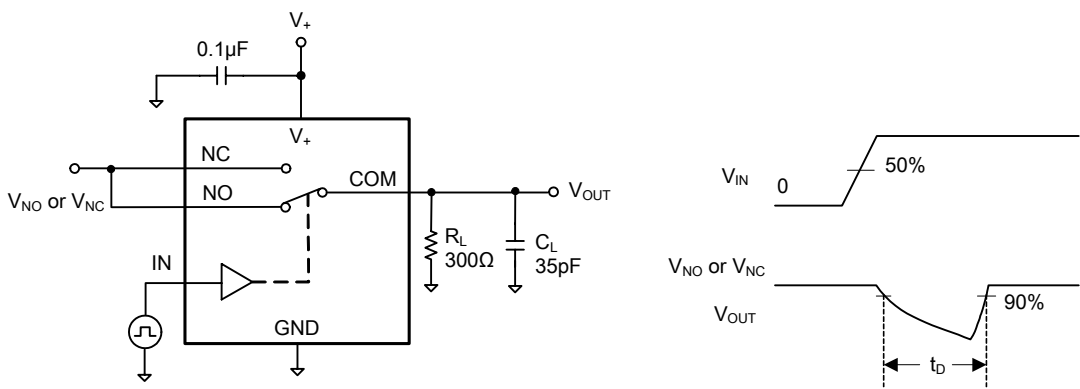
TEST CIRCUITS



Test Circuit 1. On Resistance

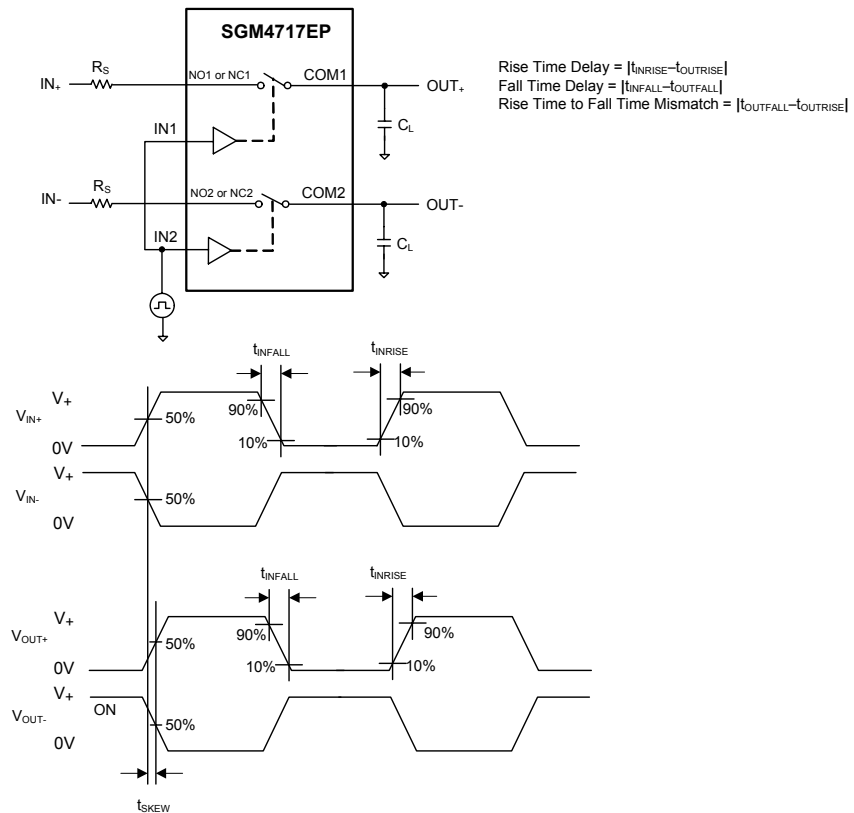


Test Circuit 2. Switching Times

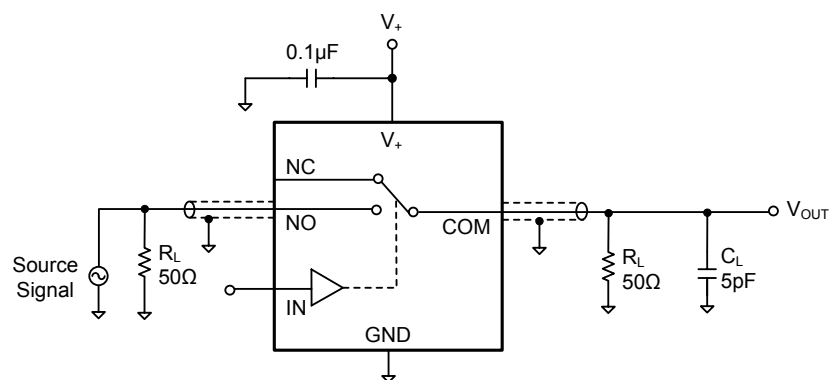


Test Circuit 3. Break-Before-Make Time Delay, t_D

TEST CIRCUITS (Cont.)

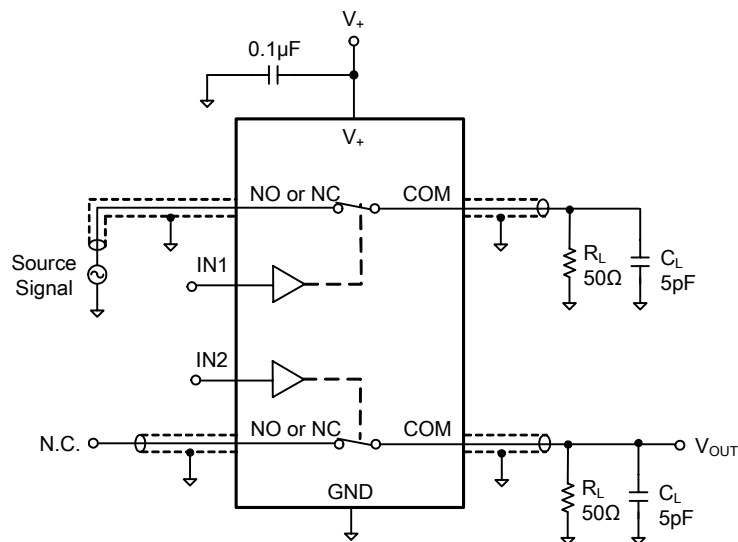


Test Circuit 4. Output Signal Skew



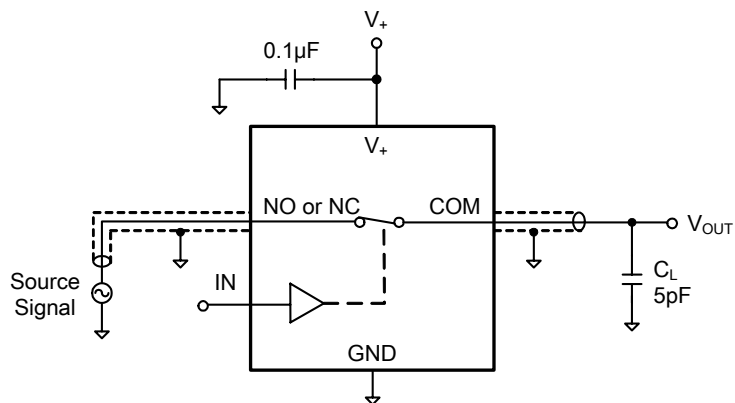
Test Circuit 5. Off Isolation

TEST CIRCUITS (Cont.)



$$\text{Channel To Channel Crosstalk} = -20 \times \log \frac{V_{\text{NO or V}_{\text{NC}}}}{V_{\text{OUT}}}$$

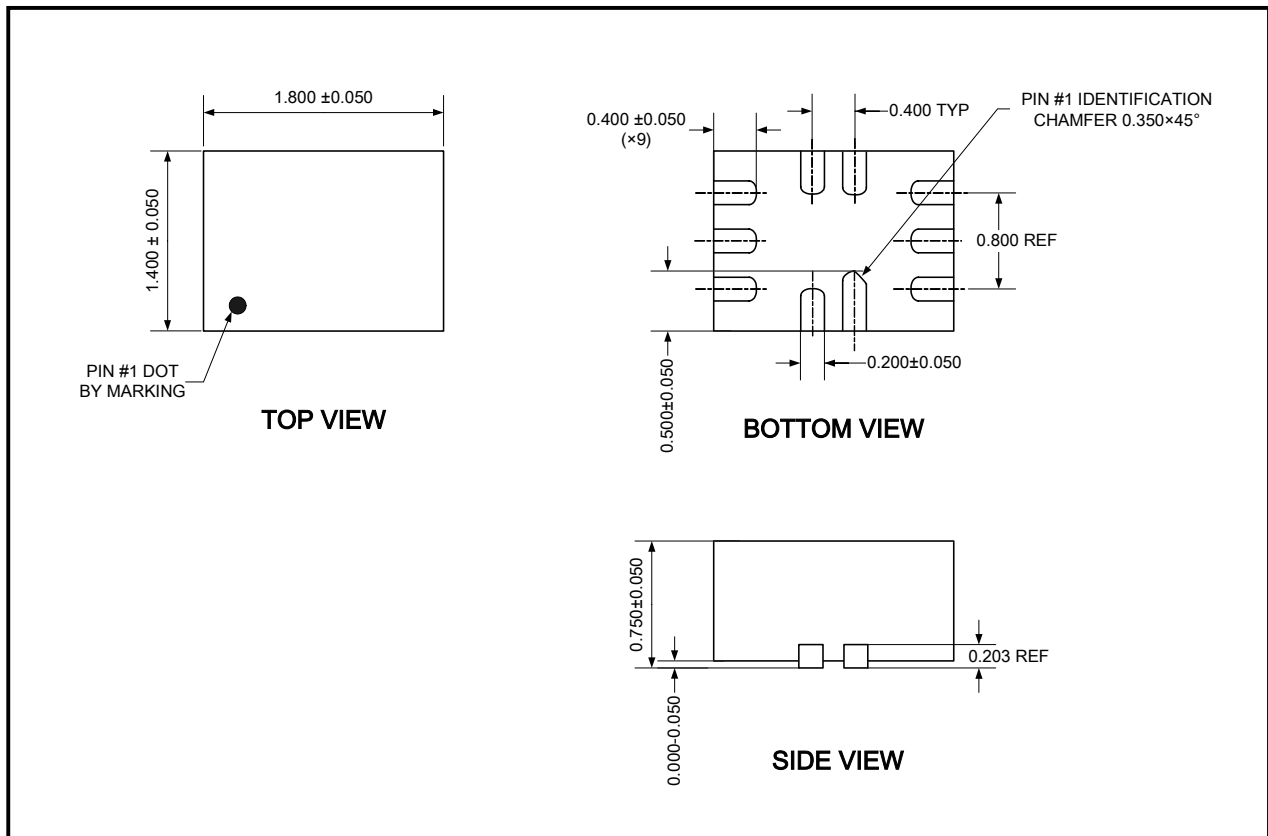
Test Circuit 6. Channel-to-Channel Crosstalk



Test Circuit 7. -3dB Bandwidth

PACKAGE OUTLINE DIMENSIONS

WQFN-10



Note: All linear dimensions are in millimeters.

03/2010 REV. B. 3

SGMICRO is dedicated to provide high quality and high performance analog IC products to customers. All SGMICRO products meet the highest industry standards with strict and comprehensive test and quality control systems to achieve world-class consistency and reliability.

For more information regarding SGMICRO Corporation and its products, please visit www.sg-micro.com

